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MOSFET – Power, N-Channel, SUPERFET[®] III, Easy Drive 650 V, 360 mΩ, 10 A

NVD360N65S3

Features

- Ultra Low Gate Charge & Low Effective Output Capacitance
- Lower FOM (R_{DS(on)} max. x Q_{g typ}. & R_{DS(on)} max. x E_{OSS})
- 100% Avalanche Tested
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V _{DSS}	650	V
Gate-to-Source Voltage - DC	V _{GSS}	±30	V
Gate-to-Source Voltage - AC (f > 1 Hz)	V _{GSS}	±30	V
Drain Current – Continuous ($T_C = 25^{\circ}C$)	I _D	10	А
Drain Current – Continuous ($T_C = 100^{\circ}C$)	I _D	6	А
Drain Current – Pulsed (Note 3)	I _{DM}	25	А
Power Dissipation $(T_C = 25^{\circ}C)$	PD	83	W
Power Dissipation – Derate Above 25°C	PD	0.67	W/°C
Operating Junction and Storage Temperature Range	T _J , T _{STG}	–55 to +150	°C
Single Pulsed Avalanche Energy (Note 4)	E _{AS}	40	mJ
Repetitive Avalanche Energy (Note 3)	E _{AR}	0.83	mJ
MOSFET dv/dt	dv/dt	100	V/ns
Peak Diode Recovery dv/dt (Note 5)	dv/dt	20	V/ns
Max. Lead Temperature for Soldering Purposes $(1/8'')$ from case for 5 s)	ΤL	300	°C

THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case, Max. (Notes 1, 2)	$R_{\theta JC}$	1.5	°C/W
Thermal Resistance, Junction-to-Ambient, Max. (Notes 1, 2, 6)	R_{\thetaJA}	52	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted.
- Assembled to an infinite heatsink with perfect heat transfer from the case (assumes 0 K/W thermal interface).
- 3. Repetitive rating: pulse-width limited by maximum junction temperature.
- 4. $I_{AS} = 2.1 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$.
- 5. $I_{SD} = 5 \text{ A}$, di/dt $\leq 200 \text{ A}/\mu \text{s}$, $V_{DD} \leq 400 \text{ V}$, starting $T_J = 25^{\circ}\text{C}$.
- 6. Device on 1 in² pad 2 oz copper pad on 1.5 x 1.5 in. board of FR-4 material.



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V _{DSS}	R _{DS(ON)} MAX I _D MAX	
650 V	360 mΩ @ 10 V	10 A





ORDERING INFORMATION

Device	Package	Shipping [†]
NVD360N65S3	DPAK3 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage	BV _{DSS}	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650			V
Drain-to-Source Breakdown Voltage	BV _{DSS}	V_{GS} = 0 V, I_D = 1 mA, T_J = 150°C	700			V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/ \Delta T_J$	$I_D = 1$ mA, Referenced to 25°C		650		mV/°C
Zero Gate Voltage Drain Current	I _{DSS} V _{GS} = 0 V, V _{DS} = 650 V				1	μΑ
		V_{DS} = 520 V, T_C = 125°C		0.33		
Gate-to-Body Leakage Current	I _{GSS}	V_{GS} = ±30 V, V_{DS} = 0 V			±100	nA
ON CHARACTERISTICS	·		•			
Gate Threshold Voltage	V _{GS(th)}	$V_{GS} = V_{DS}$, $I_D = 0.2 \text{ mA}$	2.5		4.5	V
Threshold Temperature Coefficient	$\Delta V_{GS(th)} / \Delta T_J$	$V_{GS} = V_{DS}, I_D = 0.2 \text{ mA}$		-8.8		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		314	360	mΩ
Forward Transconductance	9FS	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		6		S
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{iss}			756		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 400 V, f = 1 MHz		17.4		-
Reverse Transfer Capacitance	C _{rss}			1.53		_
Effective Output Capacitance	C _{oss(eff.)}	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		179		pF
Energy Related Output Capacitance	C _{oss(er.)}	$V_{DS} = 0 V$ to 400 V, $V_{GS} = 0 V$		29.3		pF
Total Gate Charge at 10 V	Q _{G(TOT)}			16.8		nC
Threshold Gate Charge	Q _{G(TH)}	V_{GS} = 10 V, V_{DS} = 400 V, I_{D} = 5 A		2.8		_
Gate-to-Source Gate Charge	Q _{GS}	(Note 7)		4.6		
Gate-to-Drain "Miller" Charge	Q _{GD}			7		
Equivalent Series Resistance	ESR	f = 1 MHz		1		Ω
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t _{d(on)}			13.6		ns
Turn-On Rise Time	t _r	V_{GS} = 10 V, V_{DD} = 400 V,		9.44		ns
Turn-Off Delay Time	t _{d(off)}	l _D = 5 A, R _g = 4.7 Ω (Note 7)		33.9		ns
Turn-Off Fall Time	t _f	(11.2		ns
SOURCE-DRAIN DIODE CHARACTER						
Maximum Continuous Source-to- Drain Diode Forward Current	۱ _S	V _{GS} = 0 V			10	A
Maximum Pulsed Source-to-Drain Diode Forward Current	I _{SM}	V _{GS} = 0 V		25	Α	
Source-to-Drain Diode Forward Voltage	V _{SD}	V _{GS} = 0 V, I _{SD} = 5 A			1.2	V
Reverse Recovery Time	t _{rr}			197		ns
Charge Time	t _a	V _{GS} = 0 V, dI _F /dt = 100 A/µs,		18		1
Discharge Time	t _b	$I_{SD} = 5 \text{ A}$		10		1
Reverse Recovery Charge	Q _{rr}			2089		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 7. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS



Figure 1. On-Region Characteristics 25°C



Figure 3. Transfer Characteristics







Figure 2. On–Region Characteristics 150°C





TYPICAL CHARACTERISTICS



Figure 11. Maximum Safe Operating Area











TYPICAL CHARACTERISTICS



Figure 13. E_{OSS} vs. Drain to Source Voltage



Figure 14. Normalized Gate Threshold Voltage vs. Temperature



Figure 15. Transient Thermal Response Curve







Figure 17. Resistive Switching Test Circuit & Waveforms







Figure 19. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE)

CASE 369C **ISSUE F**



ALTERNATE CONSTRUCTIONS





STYLE 6:	STYLE 7:	STYLE 8:	STYLE 9:	STYLE 10:
PIN 1. MT1	PIN 1. GATE	PIN 1. N/C	PIN 1. ANODE	PIN 1. CATHODE
2. MT2	2. COLLECTOR	2. CATHODE	2. CATHODE	2. ANODE
3. GATE	3. EMITTER	3. ANODE	RESISTOR ADJUST	3. CATHODE
4. MT2	4. COLLECTOR	4. CATHODE	4. CATHODE	4. ANODE

SOLDERING FOOTPRINT*

4. ANODE



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: INCHES.
 THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
 DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
 DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

- PLANE H. 7. OPTIONAL MOLD FEATURE

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.028	0.045	0.72	1.14
b3	0.180	0.215	4.57	5.46
C	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
Е	0.250	0.265	6.35	6.73
е	0.090 BSC		2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.114 REF		2.90 REF	
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

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